## Application/Control No. Applicant(s)/Patent Under Reexamination HEIDEL ET AL. Examiner Jonathan R. Miller Applicant(s)/Patent Under Reexamination HEIDEL ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,420,406	05-1995	Izawa et al.	235/379
	В	US-			
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	D	US-			
	E	US-			
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## NON-PATENT DOCUMENTS

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